# BULK128D-B

# HIGH VOLTAGE FAST-SWITCHING NPN POWER TRANSISTOR

- STMicroelectronics PREFERRED SALESTYPE
- INTEGRATED ANTIPARALLEL COLLECTOR-EMITTER DIODE
- NPN TRANSISTOR
- HIGH VOLTAGE CAPABILITY
- LOW SPREAD OF DYNAMIC PARAMETERS
- MINIMUM LOT-TO-LOT SPREAD FOR RELIABLE OPERATION
- VERY HIGH SWITCHING SPEED

### **APPLICATIONS:**

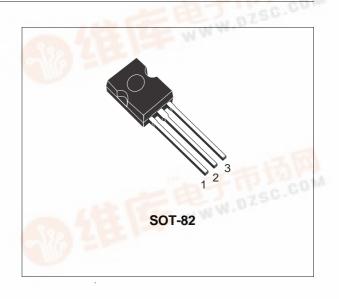
- ELECTRONIC BALLASTS FOR
  FLUORESCENT LIGHTING
- FLYBACK AND FORWARD SINGLE TRANSISTOR LOW POWER CONVERTERS

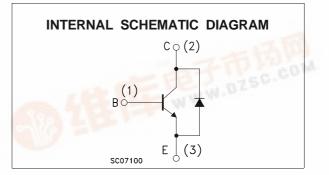
### DESCRIPTION

The device is manufactured using high voltage Multi Epitaxial Planar technology for high switching speeds and medium voltage capability.

It uses a Cellular Emitter structure with planar edge termination to enhance switching speeds while maintaining the wide RBSOA.

The device is designed for use in lighting applications and low cost switch-mode power supplies.





Symbol	Parameter	Value	Unit V	
V <sub>CES</sub>	Collector-Emitter Voltage (V <sub>BE</sub> = 0)	700		
Vceo	Collector-Emitter Voltage (I <sub>B</sub> = 0)	400	V	
Vebo	Emitter-Base Voltage ( $I_C = 0$ , $I_B = 2$ A, $t_p < 10\mu$ s, $T_j < 150^{\circ}$ C)	BV <sub>EBO</sub>	V	
Ι <sub>C</sub>	Collector Current	4	Α	
Ісм	Collector Peak Current (t <sub>P</sub> < 5 ms)	8	Α	
IB	Base Current	2	Α	
I <sub>BM</sub>	Base Peak Current (t <sub>p</sub> < 5 ms)	4	Α	
Ptot	Total Dissipation at $T_c = 25 \ ^{\circ}C$	55	W	
T <sub>stg</sub>	Storage Temperature	-65 to 150	°C	
Τ <sub>i</sub>	Max. Operating Junction Temperature	150	°C	

#### **ABSOLUTE MAXIMUM RATINGS**



## BULK128D-B

### THERMAL DATA

R <sub>thj-case</sub>	Thermal Resistance Junction-Case	Max	2.27	°C/W
R <sub>thj-amb</sub>	Thermal Resistance Junction-Ambient	Max	80	°C/W

# **ELECTRICAL CHARACTERISTICS** ( $T_{case} = 25 \ ^{\circ}C$ unless otherwise specified)

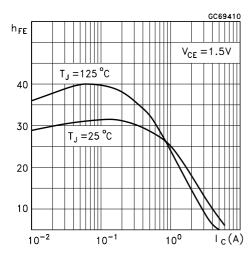
Symbol	ParameterCollector Cut-off Current (VBE = -1.5 V)	Test C	Min.	Тур.	Max.	Unit	
ICES		V <sub>CE</sub> = 700 V V <sub>CE</sub> = 700 V	T <sub>C</sub> = 125 °C			100 500	μΑ μΑ
I <sub>CEO</sub>	Collector-Emitter Leakage Current (I <sub>B</sub> = 0)	V <sub>CE</sub> = 400 V				250	μA
BV <sub>EBO</sub>	Emitter-Base Breakdown Voltage (I <sub>C</sub> = 0)	I <sub>E</sub> = 10 mA		9		18	V
$V_{CEO(sus)^*}$	Collector-Emitter Sustaining Voltage (I <sub>B</sub> = 0)	I <sub>C</sub> = 100 mA	L = 25 mH	400			V
V <sub>CE(sat)</sub> *	Collector-Emitter Saturation Voltage	I <sub>C</sub> = 0.5 A I <sub>C</sub> = 1 A I <sub>C</sub> = 2.5 A	$I_B = 0.1 A$ $I_B = 0.2 A$ $I_B = 0.5 A$			0.7 1 1.5	V V V
V <sub>BE(sat)</sub> *	Base-Emitter Saturation Voltage	$I_{C} = 0.5 A$ $I_{C} = 1 A$ $I_{C} = 2.5 A$	$I_{B} = 0.1 A$ $I_{B} = 0.2 A$ $I_{B} = 0.5 A$			1.1 1.2 1.3	V V V
h <sub>FE</sub> *	DC Current Gain	$I_C = 10 \text{ mA}$ $I_C = 2 \text{ A}$	V <sub>CE</sub> = 5 V V <sub>CE</sub> = 5 V	10 8		40	
Vf	Forward Voltage Drop	$I_f = 2 A$				2.5	V
t <sub>s</sub> t <sub>f</sub>	RESISTIVE LOAD Storage Time Fall Time	V <sub>CC</sub> = 250 V I <sub>B1</sub> = 0.4 A T <sub>p</sub> = 30 μs	$I_{C} = 2 A$ $I_{B2} = -0.4 A$ (see fig. 2)	2	0.2	2.9	μs μs
t <sub>s</sub> t <sub>f</sub>	INDUCTIVE LOAD Storage Time Fall Time		$I_{C} = 2 A$ $V_{BE(off)} = -5 V$ $L = 200 \mu H$		0.6 0.1		μs μs

 $\ast$  Pulsed: Pulse duration = 300  $\mu s,$  duty cycle 1.5 %

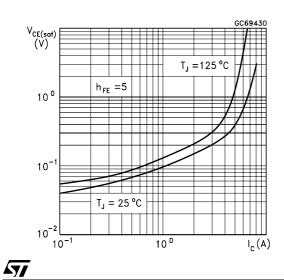
#### $I_{c}(A)$ I<sub>C</sub> MAX PULSED PULSE OPERATION \* 10<sup>1</sup> $10 \mu s$ Ic MAX CONT 100 μs 10<sup>0</sup> 500 μs D.C. OPERATION 10 , ms For single non repetitive pulse $10^{-2}$ 10<sup>1</sup> 4 6 <sup>8</sup>10<sup>2</sup> 10<sup>0</sup> <sup>4</sup>V<sub>CE</sub><sup>6</sup>(V)

### DC Current Gain

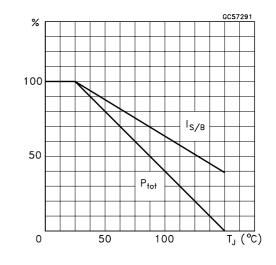
Safe Operating Areas



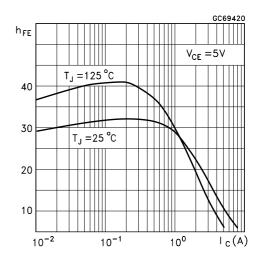
Collector Emitter Saturation Voltage



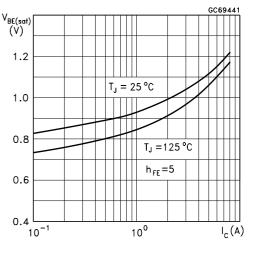
# Derating Curve



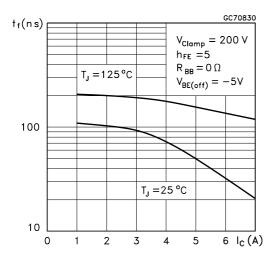
### DC Current Gain



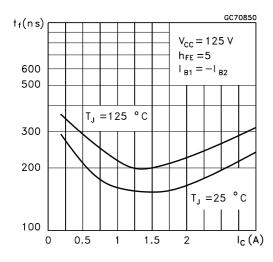
Base Emitter Saturation Voltage



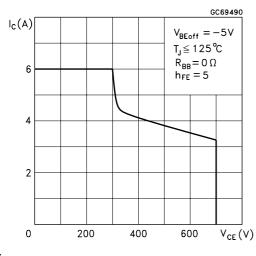
### Inductive Fall Time



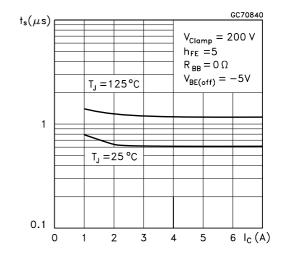
Resistive Load Fall Time

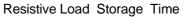


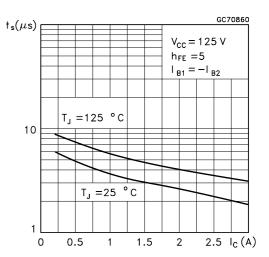
**Reverse Biased SOA** 



Inductive Storage Time







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4/7

Figure 1: Inductive Load Switching Test Circuit.

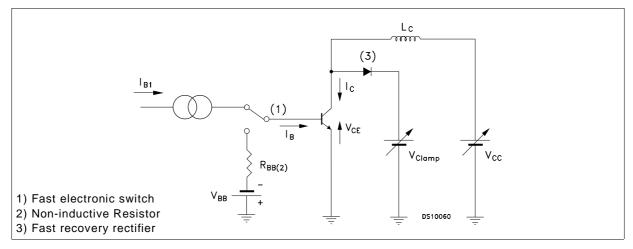
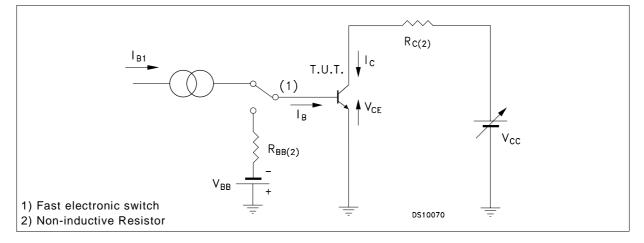


Figure 2: Resistive Load Switching Test Circuit.

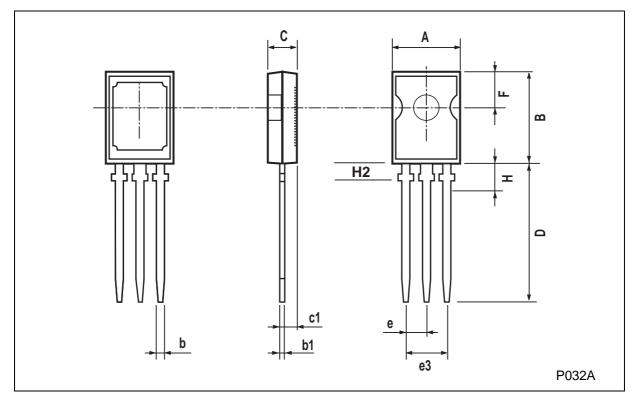
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# BULK128D-B

DIM.	mm			inch			
2	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.	
А	7.4		7.8	0.291		0.307	
В	10.5		10.8	0.413		0.444	
b	0.7		0.9	0.028		0.035	
b1	0.49		0.75	0.019		0.030	
С	2.4		2.7	0.04		0.106	
c1	1.0		1.3	0.039		0.05	
D	15.4		16	0.606		0.629	
е		2.2			0.087		
e3	4.15		4.65	0.163		0.183	
F		3.8			0.150		
Н			2.54		0.100		
H2		2.15			0.084		

# SOT-82 MECHANICAL DATA



57

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